IN THE CLAIMS

Please amend the claims as follows. This listing of claims replaces all prior versions and listings of claims in the application:

1. (Currently Amended) A method for monitoring a manufacturing process of a plurality of physical objects, the method comprising ~~the steps of automatically, without human intervention~~:

automatically, without human intervention, carrying out the steps of:

performing an analysis using values of at least one process parameter of the manufacturing process of the plurality of physical objects;

determining that at least one physical object of the plurality of physical objects does not satisfy a prescribed selection criterion;

marking the at least one physical object in such a way that the at least one marked physical object must be sent for a special measurement; and

removing the at least one marked physical object from the manufacturing process.

2. (Previously Presented) The method of claim 1 wherein the physical object is a wafer.

3. (Previously Presented) The method of claim 1 wherein the analysis is a statistical analysis.

4. (Previously Presented) The method of claim 1 wherein the values of the at least one process parameter are measured when the plurality of physical objects is being manufactured.

5. (Previously Presented) The method of claim 1, further comprising:

sending the at least one marked physical object for a special measurement.

6. (Previously Presented) The method of claim 5 wherein the special measurement is a measurement for checking the quality of the at least one marked physical object.

7. (Previously Presented) The method of claim 1, further comprising:

continuing the manufacturing process for any of the plurality of physical objects not marked as failing the prescribed selection criterion.

8. (Previously Presented) The method of claim 1, wherein the selection criterion is a quality characteristic of the manufacturing process.

9. (Previously Presented) The method of claim 1, wherein the selection criterion is not satisfied if a value of the at least one process parameter goes above or below a prescribed limit value.

10. (Currently Amended) A device for monitoring a manufacturing process of a plurality of physical objects with a processor which is set up in such a way to perform method steps, the method steps comprising ~~that the following method steps are carried out automatically, without human intervention~~:

automatically, without human intervention, carrying out the steps of:

performing an analysis using values of at least one process parameter of the manufacturing process of the plurality of physical objects;

marking at least one physical object when, as a result of the analysis, the at least one physical object does not satisfy a prescribed selection criterion;

removing the at least one marked physical object from the manufacturing process; and

sending the at least one marked physical object for special treatments.

11. (Currently Amended) A computer-readable storage medium, in which a program for monitoring a manufacturing process of a plurality of physical objects is stored, the program performing method steps comprising ~~the following method steps automatically, without human intervention~~:

automatically, without human intervention, carrying out the steps of:

performing analysis using values of at least one process parameter of the manufacturing process of the plurality of physical objects;

marking at least one ~~of~~ physical object when, as a result of the analysis, the at least one physical object does not satisfy a prescribed selection criterion;

removing the at least one marked physical object from the manufacturing process; and

sending the at least one marked physical object for special treatments.

12. (Currently Amended) A computer program element for monitoring a manufacturing process of a plurality of physical objects, the computer program comprising ~~executing the following method steps automatically, without human intervention~~:

automatically, without human intervention, executing the steps of:

performing an analysis using values of at least one process parameter of the manufacturing process of the plurality of physical objects;

marking at least one physical object when, as a result of the analysis, the at least one physical object does not satisfy a prescribed selection criterion;

removing the at least one marked physical object from the manufacturing process; and

sending the at least one marked physical object for special treatments.

13. (Currently Amended) ~~The method of claim 1, further comprising:~~ A method for monitoring a manufacturing process of a plurality of physical objects, the method comprising:

performing an analysis using values of at least one process parameter of the manufacturing process of the plurality of physical objects;

determining that at least one physical object of the plurality of physical objects does not satisfy a prescribed selection criterion;

marking the at least one physical object in such a way that the at least one marked physical object must be sent for a special measurement;

removing the at least one marked physical object from the manufacturing process; and

preventing values associated with the at least one marked physical object from affecting an average product quality of the plurality of physical objects.

14. (Currently Amended) ~~The device of claim 10, wherein the processor is further set up to carry out the set of:~~ A device for monitoring a manufacturing process of a plurality of physical objects with a processor which is set up in such a way to perform method steps, the method steps comprising:

performing an analysis using values of at least one process parameter of the manufacturing process of the plurality of physical objects;

marking at least one physical object when, as a result of the analysis, the at least one physical object does not satisfy a prescribed selection criterion;

removing the at least one marked physical object from the manufacturing process;

sending the at least one marked physical object for special treatments; and

preventing values associated with the at least one marked physical object from affecting an average product quality of the plurality of physical objects.

15. (Currently Amended) ~~The computer-readable storage medium of claim 11, wherein the program further performs the step of:~~ A computer-readable storage medium, in which a program for monitoring a manufacturing process of a plurality of physical objects is stored, the program performing method steps comprising:

performing analysis using values of at least one process parameter of the manufacturing process of the plurality of physical objects;

marking at least one ~~of~~ physical object when, as a result of the analysis, the at least one physical object does not satisfy a prescribed selection criterion;

removing the at least one marked physical object from the manufacturing process;

sending the at least one marked physical object for special treatments; and

preventing values associated with the at least one marked physical object from affecting an average product quality of the plurality of physical objects.

16. (Currently Amended) ~~The Computer program element of claim 12, wherein the computer program further executes the step of:~~ A computer program element for monitoring a manufacturing process of a plurality of physical objects, the computer program comprising:

performing an analysis using values of at least one process parameter of the manufacturing process of the plurality of physical objects;

marking at least one physical object when, as a result of the analysis, the at least one physical object does not satisfy a prescribed selection criterion;

removing the at least one marked physical object from the manufacturing process;

sending the at least one marked physical object for special treatments; and

preventing values associated with the at least one marked physical object from affecting an average product quality of the plurality of physical objects.